



Date Mailed April 15, 2003

Sheet 1 of 2

FORM 1449
SUBSTITUTE DISCLOSURE STATEMENT
IN AN APPLICATION
(Use several sheets if necessary)

Docket Number:
10873.792USD1Application Number:
10/848,742

Applicant: HIRAMOTO et al.

Filing Date: August 16, 2004 Group Art Unit: 1775

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
KB	5,390,061	02.1995	NAKATANI ET AL.			
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						YES
KB	0,913,830	05.1999	EP			
KB	1 033 764	09.2000	EP			
KB	199 34 009	01.2000	DE			SEE IDS

EXAMINER /Kevin Bernatz/

DATE CONSIDERED 10/23/2006

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.

*Substitute Disclosure Statement Form (PTO-1449)

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Sheet 2 of 2

FORM 1449 ^a INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION (Use several sheets if necessary)		Docket Number: 10873.792USDI	Application Number: 09/748,742 10/848,742
		Applicant: HIRAMOTO et al.	
		Filing Date: August 14, 2001	Group Art Unit: 1775

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
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KB		Proceedings of 112th Study Group of the Magnetic Society of Japan pp. 35-42

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EXAMINER	/Kevin Bernatz/	DATE CONSIDERED	10/23/2006
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